



Docket No.: H6808.0039/P039
(PATENT)

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:
Yuuki Ojima et al.

Application No.: 10/779,848

Confirmation No.: 9446

Filed: February 18, 2004

Art Unit: 2881

For: SCANNING ELECTRON MICROSCOPE
WITH MEASUREMENT FUNCTION

Examiner: J. L. Smith

AMENDMENT IN RESPONSE TO NON-FINAL OFFICE ACTION

MS Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Dear Sir:

INTRODUCTORY COMMENTS

In response to the Office Action dated May 3, 2005, please amend the above-identified U.S. patent application as follows:

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 4 of this paper.